Simulation of carrier dynamics in graphene on a substrate at terahertz and mid-infrared frequencies

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Abstract—We calculate the complex conductivity of graphene in the terahertz (THz) to mid-infrared (mid-IR) frequency range using a numerical simulation that couples the two-dimensional (2D) ensemble Monte Carlo technique (EMC) for carrier transport, the three-dimensional (3D) finite-difference time-domain (FDTD) technique for electrodynamics, and molecular dynamics (MD) for short range Coulomb interactions. We demonstrate the effect of the typically used silicon-dioxide substrate on the high-frequency carrier dynamics in graphene and show good agreement between recent experimental results and our numerical simulations.

I. INTRODUCTION

Graphene is a promising material for novel electronic and optoelectronic device applications [1]–[3]. Although considerable work has been done on the fundamental electronic properties [4] and low-field dc transport [5] in graphene, high-frequency carrier dynamics in this material has not been extensively studied [6]. From a technological perspective, the application of graphene in optoelectronic devices, such as transparent conductors, photodetectors, and metamaterials, requires a deeper understanding of the interaction of high-frequency electromagnetic waves with the carriers in this two-dimensional system. Moreover, the effect of a substrate and the impurities therein cannot be ignored for device applications.

II. NUMERICAL MODEL

Here, we calculate the frequency-dependent conductivity of graphene and demonstrate the effect of a typical SiO$_2$ substrate on the carrier dynamics. Our numerical simulation combines the ensemble Monte Carlo (EMC) technique for solving the Boltzmann transport equation for carrier transport in the two-dimensional (2D) graphene layer with the three-dimensional (3D) finite-difference time-domain (FDTD) technique [7] for solving Maxwell’s curl equations throughout the domain. The short-range Coulomb forces exerted on the carriers by impurity ions are calculated using molecular dynamics (MD). The EMC, FDTD, and MD solvers are coupled in each time step, such that the combined FDTD-MD fields accelerate the carriers and the EMC carrier motion produces the sourcing current density. This coupled EMC-FDTD-MD technique has previously been used to accurately calculate the ac conductivity of doped silicon [8], [9].

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The simulation domain, as shown in Fig. 1a, consists of a monolayer graphene sheet with air on top and a SiO$_2$ substrate at the bottom, with dielectric constants of $\epsilon_g = 2.5$, $\epsilon_{air} = 1.0$, and $\epsilon_{SiO_2} = 3.9$, respectively. We use periodic boundary conditions for the bounding planes perpendicular to the plane of carrier transport (the xz and yz planes in Fig. 1a), in order to simulate a very large sheet of graphene. The simulation domain is terminated with convolutional perfectly matched layer (CPML) boundary conditions [7] on the top and bottom boundaries. The initial electric field distribution due to the carriers and charged impurities is shown in Fig. 1b.

The 2D carrier transport is limited by the Coulomb fields of the impurities in the substrate, in addition to scattering with longitudinal acoustic (LA) and optical (LO) phonons, as well as polar surface optical (SO) phonons due to the substrate. The LA and LO scattering rates are calculated based on the interaction Hamiltonian from Ref. [11], and the TBB electron-phonon scattering rates to deduce the deformation potentials [10]. The SO scattering rates are calculated based on the interaction Hamiltonian from Ref. [11], and the TBB wave functions.

III. RESULTS

Ensemble averages of the drift velocity, carrier density, and energy are calculated at each time step. Fig. 2 shows the time evolution of the carrier velocity for a 13 THz plane wave.
excitation, with electric field along the y-direction. Current density and electric field phasors are calculated using fast Fourier transform after a steady state has been reached, and are used to calculate complex conductivity based on the formula \[ \sigma(\omega) = \frac{E(\omega)J(\omega)}{|E(\omega)|^2}. \] In Fig. 3, we show the real part of the complex conductivity as a function of frequency for supported and unsupported (suspended) graphene with a carrier density of \(6.3 \times 10^{12} \text{ cm}^{-2}\). We contrast transport in a suspended graphene sheet, where the intrinsic LA and LO phonon-electron scattering limits carrier dynamics, with transport in supported graphene, where the inclusion of SO phonon-electron and impurity scattering is necessary. A significant effect on the conductivity of graphene due to the SO phonons (red squares) as well as the impurities (green diamonds and pink triangles) is clearly seen in Fig. 3. For example, the conductivities of suspended graphene (blue squares) at 4 THz (\(\text{Re} \{\sigma\} = 3.8 \text{ e}^2/\text{h}\)) and 10 THz (\(\text{Re} \{\sigma\} = 1.6 \text{ e}^2/\text{h}\)) are lower than those of supported graphene without impurities (red squares) by factors of 6 and 3, respectively. In contrast, at frequencies below 1 THz, the conductivity of suspended graphene exceeds that of supported graphene. We find good agreement with the experimental data [6] (black curve) corresponding to the same carrier density tuned via a gate voltage of 50 V, for a simulation with an impurity density that is twice the carrier density.

IV. CONCLUSION

In conclusion, we have calculated the complex conductivity of graphene in the THz to mid-IR frequency range by simulating the high frequency carrier dynamics using a coupled EMC-FDTD-MD numerical solver. We demonstrate that the substrate has a significant influence on carrier transport at low frequencies, while its influence becomes less pronounced at frequencies greater than 10 THz. Our results show good agreement with recent experimental data [6] for practically relevant carrier and substrate impurity densities. Moreover, we can independently tune the impurity density and also predict the frequency dependent conductivity of graphene supported on an ideally clean SiO\(_2\) substrate. Such a characterization of the high-frequency conductivity of supported and gated graphene might provide useful for photonic and optoelectronic device applications.

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